

February 25 – 27, 2019

The Florida Hotel & Conference Center | Orlando, Florida

1500 Sand Lake Road, Orlando, Florida 32809

1-800-588-4656

## **TE- 14 | February 26 & 27 | 8:00 AM - 5:00 PM | 2-Day (16 hours)**

### **Course Title:** Dimensional Metrology Hands-On Workshop

**Instructors:** Ted Doiron, National Institute of Standards and Technology (NIST)

Eric Stanfield, National Institute of Standards and Technology (NIST)

**Course Description:** The basic principles of dimensional metrology are the same for nearly every calibration made in typical labs. This workshop teaches these principles through guided hands-on characterization of the most typical dimensional measurement instrument, the Universal Length Measuring Machine.

#### **Instructor Biographies:**

Ted Doiron is the Leader of the Dimensional Metrology Group at NIST. He has been a dimensional metrologist at NIST for 30 years and has experience in both NMI and manufacturing level measurements. As the Quality Manager for his Division and over 100 assessments of laboratories to ISO 17025 he has seen the problems of determining calibration uncertainty at all levels of the national measurement system.

Mr. Stanfield is a Dimensional Metrologist/Mechanical Engineer within the Dimensional Metrology Group (DMG) and has been at NIST for 24 years. He has an A.A.S. in Metrology which he obtained in 1991 and a B.S. in Mechanical Engineering which he earned, with honors, from George Washington University on a part-time basis while working at NIST as a technician. In addition to receiving his degree in 2004, he received the Judson C. French Award for “Outstanding Leadership in the Development of Improved Dimensional Calibration Services with High Efficiency, Accuracy, and Customer Satisfaction.” Since earning his degree in Mechanical Engineering in 2004, he has served as Project Leader for a 4-year DOE sponsored effort titled “Metrology or Fuel Cell Manufacturing” where he managed three subprojects addressing process control related solutions to enable fuel cell manufacturing. He is a graduate of both the NIST Project Management and Leadership Program and the NIST New Leaders Program. For the last two years, he served as the Project Leader for Dimensional Measurement Services but has most recently taken a special assignment to focus on getting DMG’s 3rd M48 CMM operational and characterized.